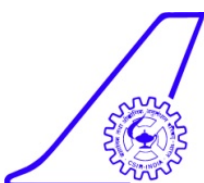
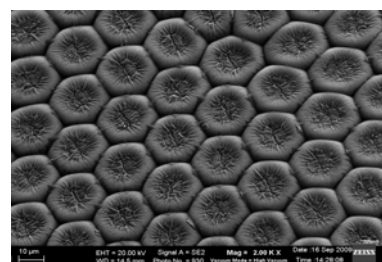
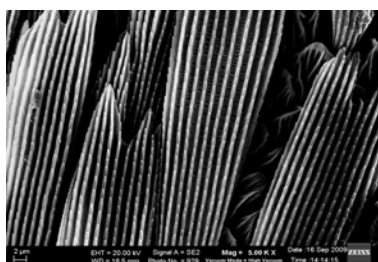
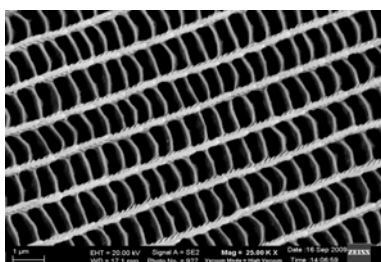
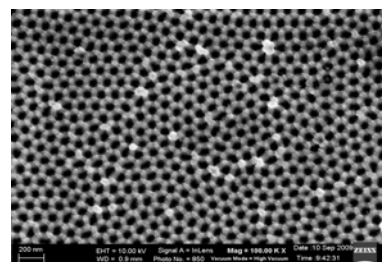
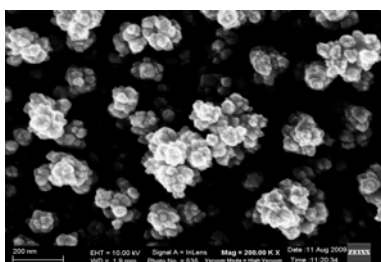
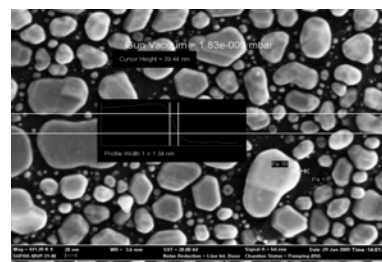
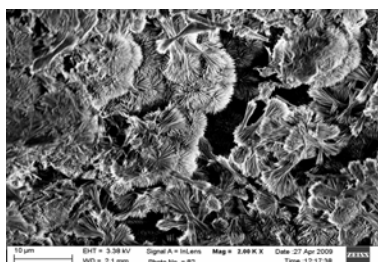
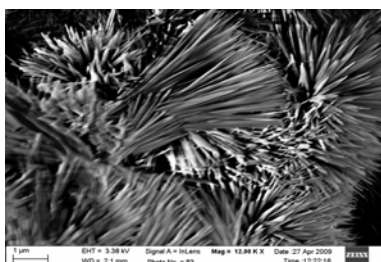


Field Emission Scanning Electron Microscopy (FESEM-Carl Zeiss, Supra 40 VP) Facility for the Characterization of Nanomaterials

Salient Features:

- Resolution : **1.0 nm at 20 kVA**
- Variable pressure mode for non-conducting samples
- UHV compatible system with two ion pumps and one turbo-molecular pump : **Vacuum - 10^{-5} to 10^{-11} mbar**
- EDS for elemental detection down to **B**
- EBSD for mapping of nanocrystals of different orientations



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